

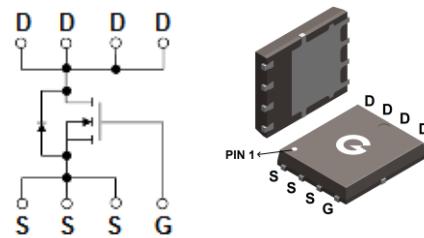
Features

- Ultra-low on-resistance and gate-charge
- HBM: JESD22-A114-B: 1A

HF

Mechanical Data

- Case: PDFN5x6-8L
- Molding Compound: UL Flammability Classification Rating 94V-0
- Terminals: Matte tin-plated leads; solderability-per MIL-STD-202, Method 208


PDFN5x6-8L

Ordering Information

Part Number	Package	Shipping Quantity	Marking Code
BL035N04T-5DL8	PDFN5x6-8L	5000 pcs / Tape & Reel	035N04T

Maximum Ratings (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V_{DSS}	40	V
Gate-to-Source Voltage	V_{GSS}	± 20	V
Continuous Drain Current ($T_c = 25^\circ\text{C}$, Silicon Limited)	I_D	118	A
Continuous Drain Current ($T_c = 25^\circ\text{C}$, Package Limited)		100	A
Continuous Drain Current ($T_c = 100^\circ\text{C}$)		75	A
Continuous Drain Current ($T_A = 25^\circ\text{C}$) ^{*1}		23	A
Continuous Drain Current ($T_A = 100^\circ\text{C}$) ^{*1}		15	A
Pulsed Drain Current ($t_p = 10\mu\text{s}$, $T_c = 25^\circ\text{C}$)	I_{DM}	400	A
Single Pulse Avalanche Energy ^{*3}	E_{AS}	100	mJ
Power Dissipation ($T_c = 25^\circ\text{C}$)	P_D	78	W
Operating Junction Temperature Range	T_J	-55 ~ +150	°C
Storage Temperature Range	T_{STG}	-55 ~ +150	°C

Thermal Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	-	1.3	1.6	°C/W
Thermal Resistance Junction-to-Air ^{*1}	$R_{\theta JA}$	-	30	40	°C/W

Electrical Characteristics (@ $T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
Static Characteristics						
V_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$	40	-	-	V
$I_{DS(0)}$	Zero Gate Voltage Drain Current	$V_{DS} = 40\text{V}$, $V_{GS} = 0\text{V}$	-	-	1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{GS} = \pm 20\text{V}$, $V_{DS} = 0\text{V}$	-	-	± 100	nA
On Characteristics						
$R_{DS(ON)}$	Drain-Source On-resistance ^{*2}	$V_{GS} = 10\text{V}$, $I_D = 20\text{A}$	-	2.8	3.5	$\text{m}\Omega$
		$V_{GS} = 4.5\text{V}$, $I_D = 20\text{A}$	-	4.0	5.5	$\text{m}\Omega$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	1	1.7	2.5	V
R_G	Gate Resistance	$V_{GS} = 0\text{V}$, $f = 1\text{MHz}$	-	4.7	-	Ω
Dynamic Characteristics						
C_{ISS}	Input Capacitance	$V_{GS} = 0\text{V}$ $V_{DS} = 20\text{V}$ $f = 1.0\text{MHz}$	-	1685	-	pF
C_{OSS}	Output Capacitance		-	647	-	
C_{RSS}	Reverse Transfer Capacitance		-	9	-	
Switching Characteristics						
$t_{d(\text{ON})}$	Turn-on Delay Time ^{*4}	$V_{DD} = 20\text{V}$ $V_{GS} = 10\text{V}$ $R_G = 6\Omega$ $R_L = 1\Omega$	-	9	-	ns
t_r	Turn-on Rise Time ^{*4}		-	51	-	
$t_{d(\text{OFF})}$	Turn-Off Delay Time ^{*4}		-	46	-	
t_f	Turn-Off Fall Time ^{*4}		-	78	-	
Q_G	Total Gate-Charge	$V_{DD} = 20\text{V}$ $V_{GS} = 10\text{V}$ $I_D = 20\text{A}$	-	27	-	nC
Q_{GS}	Gate to Source Charge		-	4.5	-	
Q_{GD}	Gate to Drain (Miller) Charge		-	5	-	
Source-Drain Diode Characteristics						
V_{SD}	Diode Forward Voltage ^{*2}	$I_S = 20\text{A}$, $V_{GS} = 0\text{V}$	-	0.8	1.2	V
t_{rr}	Reverse Recovery Time	$I_S = 20\text{A}$, $V_{GS} = 0\text{V}$ $dI/dt = 100\text{A}/\mu\text{s}$	-	65	-	ns
Q_{rr}	Reverse Recovery Charge		-	66	-	nC

Notes:

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper
2. The data tested by pulsed, pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
3. The E_{AS} data shows Max. rating. The test condition is $V_{DD} = 20\text{V}$, $V_{GS} = 10\text{V}$, $L = 0.5\text{mH}$
4. Guaranteed by design, not subject to production

Ratings and Characteristics Curves (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

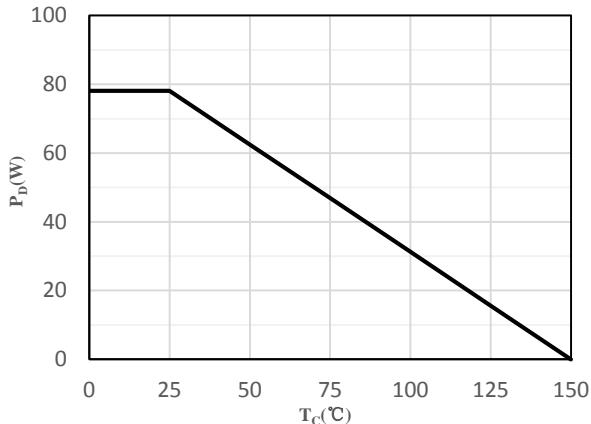


Fig 1 Power Dissipation

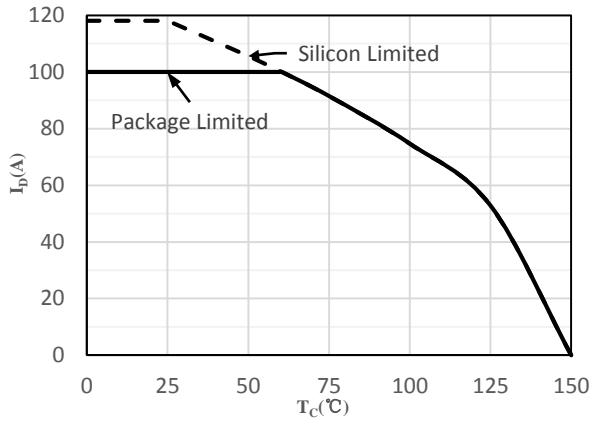


Fig 2 Drain Current

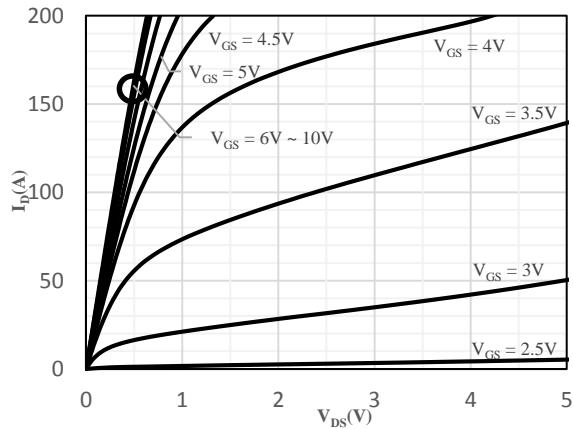


Fig 3 Typical Output Characteristics

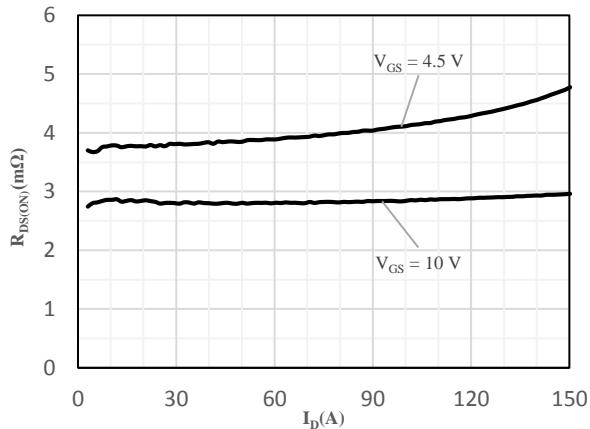


Fig 4 On-Resistance vs. Drain Current
and Gate Voltage

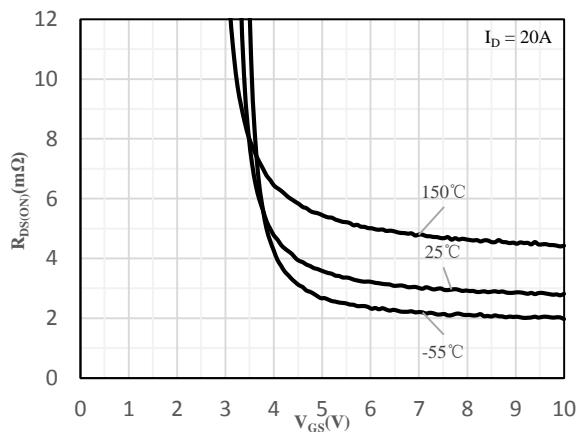


Fig 5 On-Resistance vs. Gate-Source Voltage

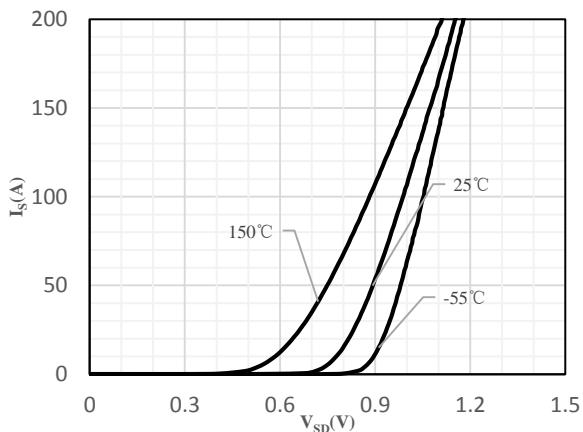


Fig 6 Body-Diode Characteristics

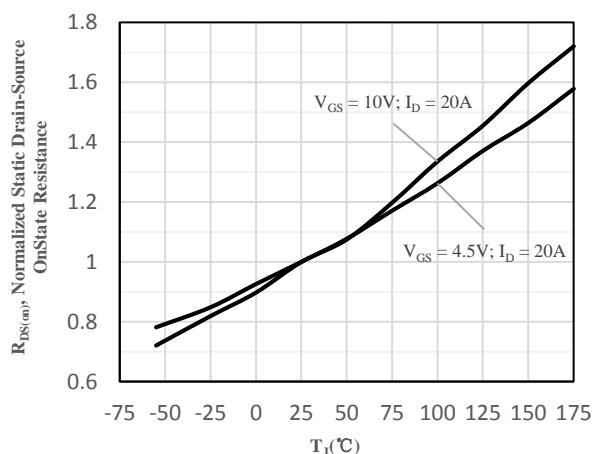


Fig 7 Normalized On-Resistance vs. Junction Temperature

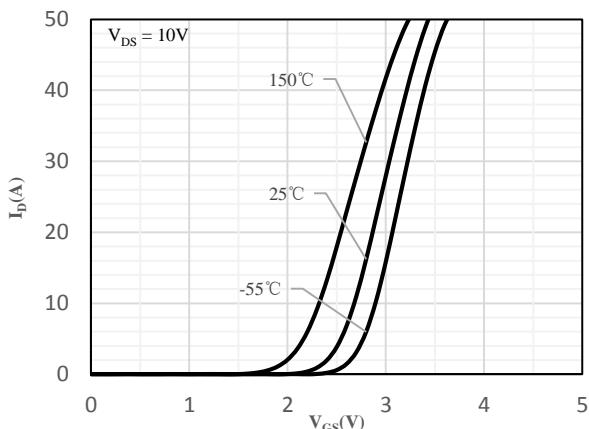


Fig 8 Transfer Characteristics

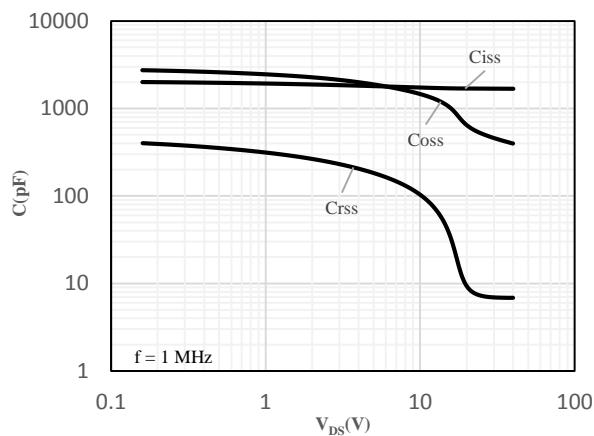


Fig 9 Capacitance Characteristics

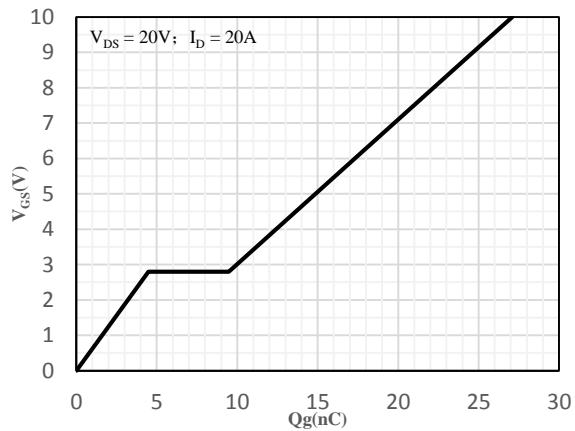


Fig 10 Gate-Charge Characteristics

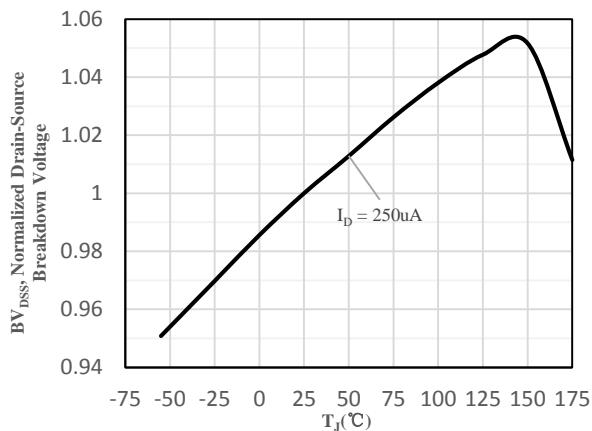


Fig 11 Normalized Breakdown Voltage vs. Junction Temperature

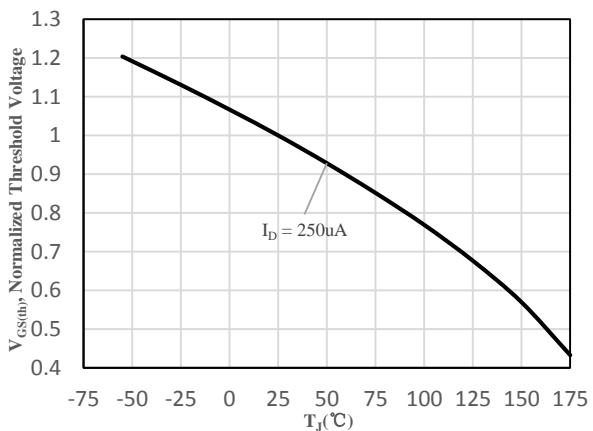


Fig 12 Normalized $V_{GS(th)}$ vs. Junction Temperature

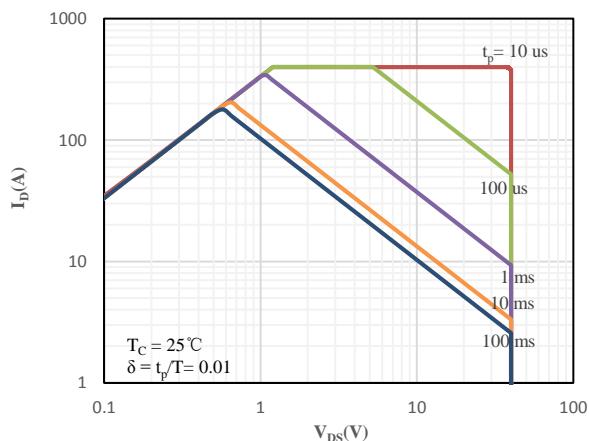


Fig 13 Safe Operation Area

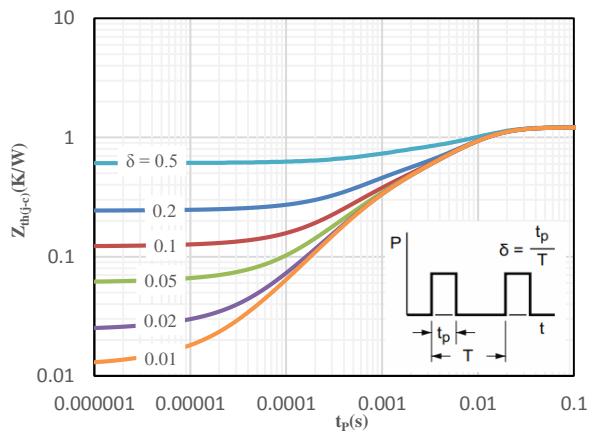
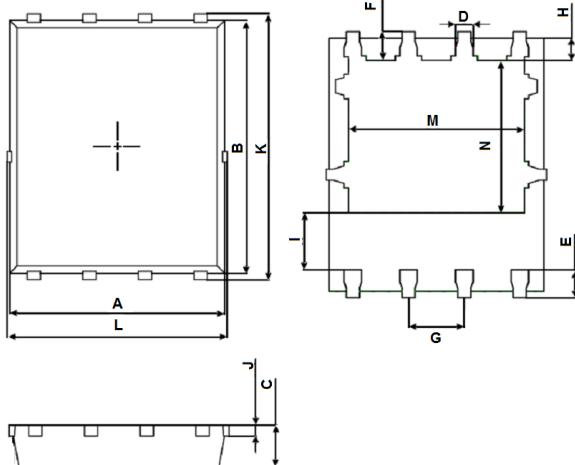


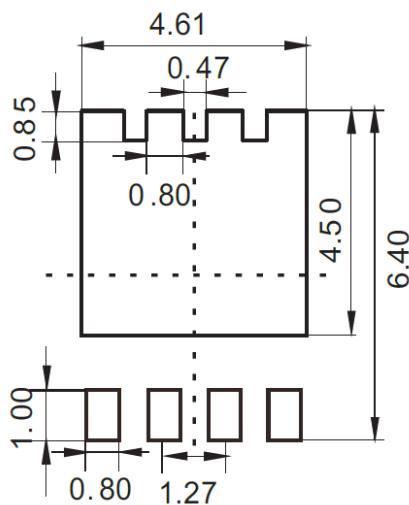
Fig 14 Maximum transient thermal impedance

Package Outline Dimensions (Unit: mm)



PDFN5x6-8L		
Dimension	Min.	Max.
A	4.824	4.976
B	5.674	5.826
C	0.900	1.000
D	0.350	0.450
E	0.559	0.711
F	0.574	0.726
G	1.250	1.290
H	0.424	0.576
I	1.190	1.390
J	0.154	0.354
K	5.974	6.126
L	4.944	5.096
M	3.910	4.110
N	3.375	3.575

Mounting Pad Layout (Unit: mm)

PDFN5x6-8L


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